

Quarterly Reliability Monitoring Results

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number PZU13B1A-Q Part Description									
								Nexperia DHAM Zener			
								SMD package			
		Test Conditions	Duration	# Lots	# Quantity	# Rejects					
			TEST								
			Pre- and Post-Stress								
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below					
		JESD22-A113									
		Bake Tamb = 125 °C	24 hours								
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours								
# A1	Preconditioning	Reflow soldering	3 cycles	1168	66640	0					
		MIL-STD-750-1									
	HTRB	M1038 Method A									
	· ,	Tj = Tjmax, VR = 80 % of rated reverse				_					
# B1	Bias	voltage	1000 hours	198	11960	0					
		MIL-STD-750-1									
		M1038 Method B									
	SSOP	Tj = Tjmax, Iz = 100% of max. datasheet			. =	_					
# B1b	Steady State Operational	reverse current	1000 hours	24	1760	0					
		150000 4404									
	TC Temperature Cycling	JESD22-A104 -65 °C to Timax, not to exceed 150°C	1000	2.40	1 1000						
# A4	remperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	240	14800	0					
		JECD22 A110									
# A3 or	UHAST Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %									
# A3 01	Olibiased HAST		- 96 hours	240	14800	0					
	AC	JESD22-A102									
# 42 ala	AC Autoclave	Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)									
# A3 alt	Autociave	riessuie – 203 kra (23.7 psia)									
	H3TRB	JESD22-A101									
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of									
# A2 alt	Temperature Reverse Bias		1000 hours	240	14800	0					
# AZ dit	. cperatare Reverse Dias	MIL-STD-750 Method 1037	1000 110015	270	14000						
	IOL	ton = toff, devices powered to insure ΔT_j =									
# A5	Intermittent Operating Life		1000 hours	264	16720	0					
# AJ	Intermittent Operating Life	100 C 101 13000 Cycles	1000 110015	204	10/20	U					
	RSH	JESD22-A111									
# C8	Resistance to Solder Heat		10 s	184	5520	0					
" CO	SD		103	107	3320						
# C10	Solderability	J-STD-002		501	5010	0					
" CIO				201	5010	<u> </u>					

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11960	0	0,36	2,82E+09

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